

2184

PATENT *Chen*

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of:

EGAN et al.

Serial No.: 09/848,109

Filed: May 2, 2001

Atty. Docket No.: 3123-355

For: "METHOD AND APPARATUS  
FOR THE DETECTION OF  
MULTIPLE SMALL DEFECTS IN  
A FLAW SCAN DETECTION  
SYSTEM"

Assistant Commissioner for Patents  
Washington, D.C. 20231



Group Art Unit: 2184

Examiner:

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OF MARCH, 2002.

*Tejpal S. Hansra*  
Tejpal S. Hansra

Dear Sir:

Please change the Correspondence Address for the above-identified patent application to:

**Tejpal S. Hansra  
Hansra Patent Services  
3705 Canterbury Lane, #6  
Bellingham, WA 98225  
Tel. (360) 527-1400  
Fax (360) 527-1450**

**RECEIVED**

**APR 09 2002**

**Technology Center 2100**

I am an attorney of record in the above-identified patent application.

Respectfully submitted,

*Tejpal S. Hansra*

Tejpal S. Hansra  
Registration No. 38,172  
Hansra Patent Services  
3705 Canterbury Lane, #6  
Bellingham, WA 98225  
(360) 527-1400

Date: MARCH 25, 2002